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DOI: 10.1002/xrs.2833

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DENVER X-RAY CONFERENCE AWARDS (August 2, 2017)

During the plenary session of the 66th Annual Denver X-Ray Conference, the following awards were presented. The 2017 Jenkins Award, recognizing lifetime achievement in the advancement of the use of X-rays in materials analysis, was presented to James Kaduk, Polycrystallography, Inc. and Illinois Institute of Technology, for his broad achievements in discovery, research, and education in the use of X-rays for materials analysis. The 2017 Barrett Award, in recognition of outstanding contributions to powder diffraction, was presented to Daniel Louer, France, for his involvement with powder diffraction in indexing, line profile analysis, and ab initio structure solution, as well as his service to the community through ICDD and EPDIC. Dr. Louer was unable to attend DXC and will accept the award at the ICDD Annual Meetings in 2018. The 2017 Jerome B. Cohen Student Award, recognizing outstanding achievements of student research in X-ray analysis, was won by Howard Joress, Cornell University, for his work, A Polycapillary-Based Method of Monochromatic Time-Resolved X-ray Reflectivity. Howard presented his work at the conference during the General XRD session. For further information, visit the Web page, http://www.dxcicdd.com/

THE 12TH ASADA AWARD (October 26, 2017)

The recipient of the 12th Asada Award, which is presented by the Discussion Group of X-ray analysis, Japan, in memory of the late Professor Ei-ichi Asada (1924–2005) to promising young scientists in X-ray analysis fields in Japan, is Dr. Koji Nakanishi (Ritsumeikan University, Kusatsu, Shiga), “Advanced instrumentation in soft-X-ray absorption spectroscopy for innovative battery research.” The ceremony was held during the 53rd Annual Conference on X-Ray Chemical Analysis, at Tokushima University, Tokushima.

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How to cite this article: Sakurai K. Professional. *X-Ray Spectrometry*. 2018;47:258. https://doi.org/10.1002/xrs.2833

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DOI: 10.1002/xrs.2970

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2018 Workshop on buried interface science with X-rays and neutrons (January 23, 2018)

The 2018 workshop on buried interface science with X-rays and neutrons was held at National Institute for Materials Science (NIMS), Tsukuba, Japan, on January 21–23, 2018. This was the latest in a series of 22 workshops held since 2001. In spite of unexpected heavy snowing, 56 scientists from all over Japan (as well as invited speakers from Malaysia and Taiwan) participated in the 2.5 days discussion. There are increasing demands for sophisticated metrology in order to observe nanolayers and interfaces in multilayered films, which are finding applications in electronic, magnetic, optical, and other devices. The transmission electron microscopy can help scientists if the cross-sectional samples are prepared and provided, but X-ray and neutron techniques is known for its ability to achieve similar atomic-scale analysis for layers and interfaces in a nondestructive manner. It ensures the subsequent analyses by other techniques. In addition to such inherent advantages, the latest progress in novel sophisticated X-ray and neutron sources could push the techniques towards further attractive applications. New detector technologies are also extremely important for new research exploring buried interfaces. The present workshop gathered together those with different research backgrounds, that is, from semiconductor electronics to chemical biomaterials, and even specialists of the accelerator, nuclear reactor, and detectors were invited to give insights into unsolved problems on buried interfaces.

New edition of Japanese X-ray reflectivity book (June 29, 2018)

Recently, new edition of “Introduction to X-ray reflectivity” has appeared in the bookstores in Japan. The book is 30% thicker than the 1st edition, which was published in January 2009. The chapters explaining fundamental contents have been strengthened by the 10% pages increase. The book includes new chapters, such as “How we need to be careful in the data analysis?” “Micro analysis and imaging of inhomogeneous thin films,” and “Operando analysis and time resolved measurements.” In the application chapters, “Liquid-solid interfaces including electro-chemical interfaces” is newly added. The contents in “Polymer films” become almost twice. As useful related techniques, “Resonant soft X-ray scattering” and “X-ray photon correlation spectroscopy” are new additions. The final chapter is “Use of neutrons.” Several good books on X-ray techniques for surfaces and interfaces are already available, but this book will be a unique addition to such collections.

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How to cite this article: Sakurai K. Professional. *X-Ray Spectrometry*. 2018;47:410. https://doi.org/10.1002/xrs.2970

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